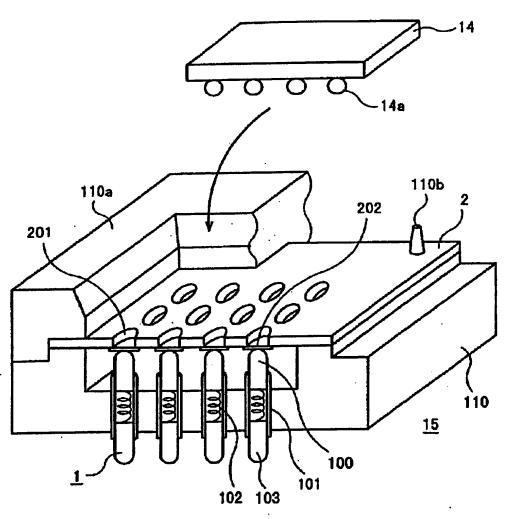
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 1 of 18

F | G. 1



2: CONNECTING SHEET 110: SOCKET BASE

100: PLUNGER 110a: SOCKET LID

101: CYLINDER 110b: ALIGNING PIN

102: COIL SPRING 201: CONNECTING HOLE

103: TERMINAL PORTION 202: ELECTRODE PAD

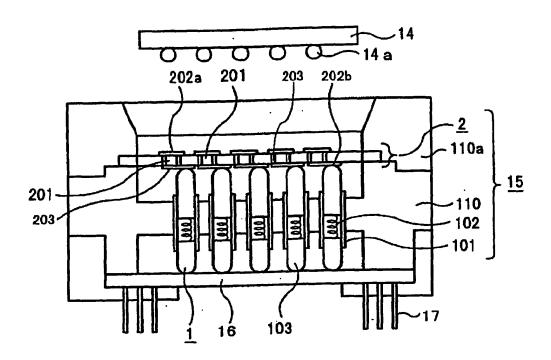
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

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INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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F I G. 2



202a, 202b: ELECTRODE PAD

203: CONNECTING WIRE

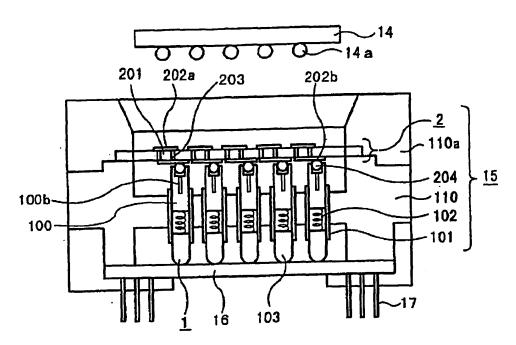
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

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INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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F 1 G. 3



100b: SLIT

204: PROJECTION-LIKE ELECTRODE

2.54

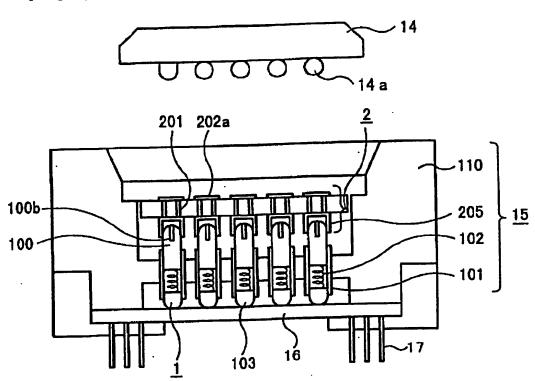
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

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INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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F 1 G. 4



100b: SLIT

205: RECESS-LIKE ELECTRODE

2.40

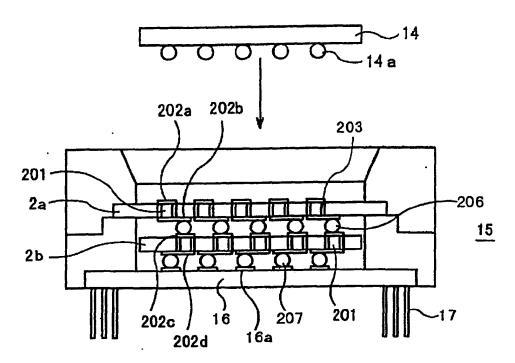
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APPLICATION SERIAL NO: 028433-012 SHEET 5 of 18

FIG.5



202a~d: ELECTRODE PAD

16a: ELECTRODE PAD

206: CONNECTING WIRE

207: CONNECTING TERMINAL

2

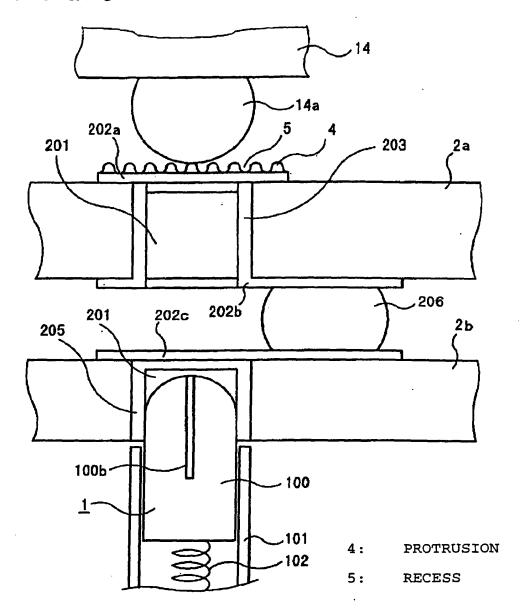
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

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INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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F 1 G. 6



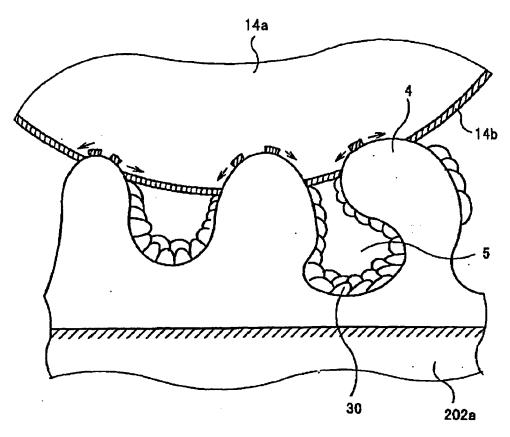
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F I G. 7



14b: OXIDE COATING

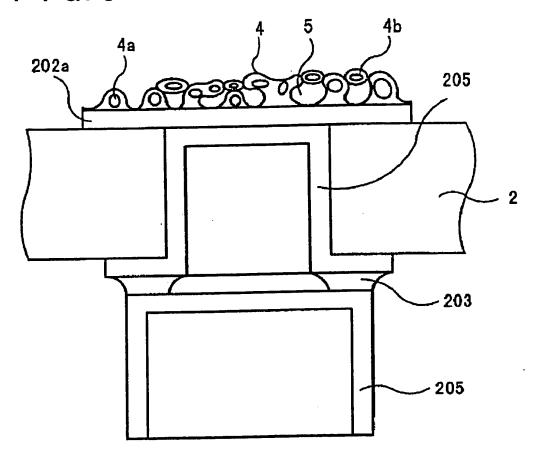
APPLN. FILING DATE: SEPTEMBER 11, 2003 **TITLE:** SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

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INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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F | G. 8



METALLIC PARTICLE 4a:

PLATING LAYER 4b:

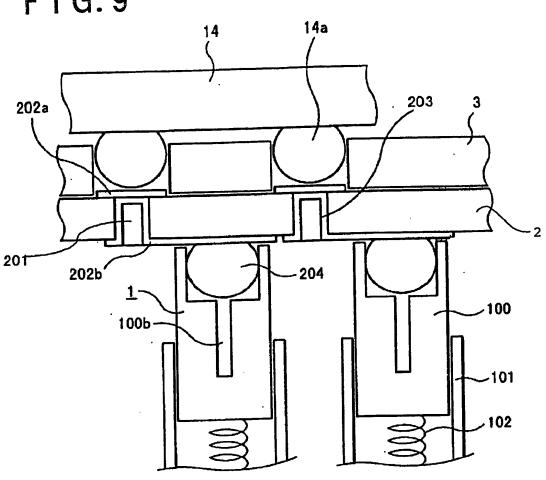
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3: GUIDING PLATE

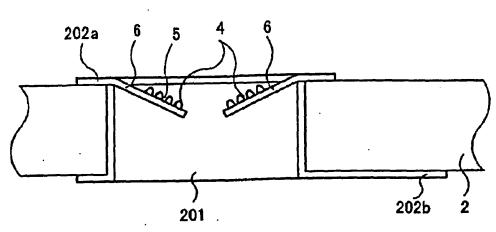
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

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Inventor(s): Shigeki maekawa et al.

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F I G. 10



6: LEAD

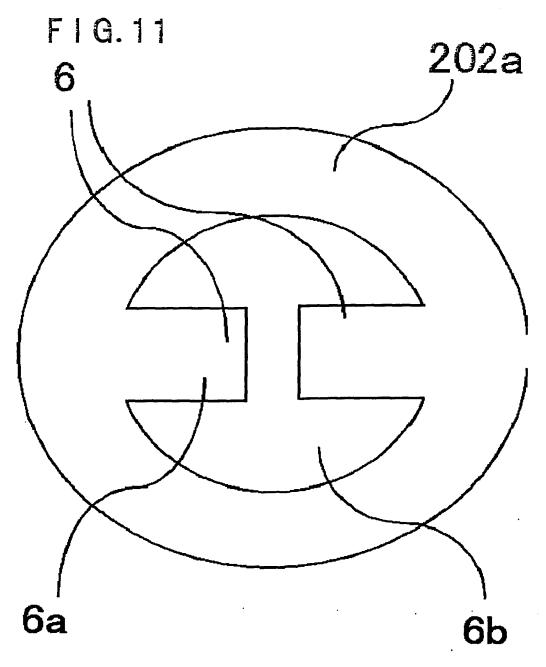
3 .44

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6: LEAD

6a: BENDING PORTION

6b: SPACED PORTION

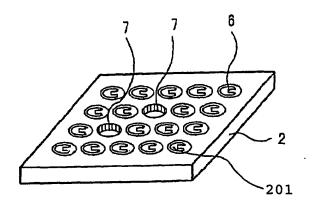
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

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INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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FIG. 12



7: THROUGH HOLE

: .~:

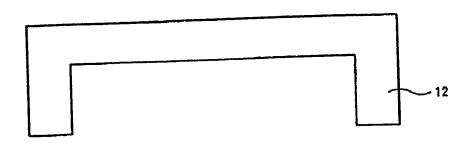
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

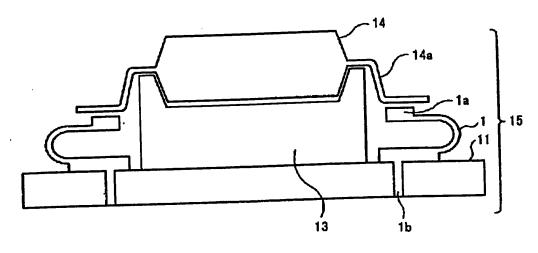
AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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FIG. 13





1: PROBE

SEAT 13:

TIP PORTION 1a:

SEMICONDUCTOR PACKAGE 14:

CONNECTING TERMINAL 1b:

14a: OUTER CONNECTING TERMINAL

HOUSING 11:

SOCKET 15:

SECURING JIG 12:

TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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FIG. 14a

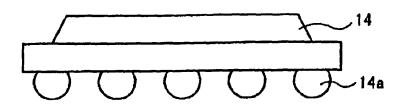
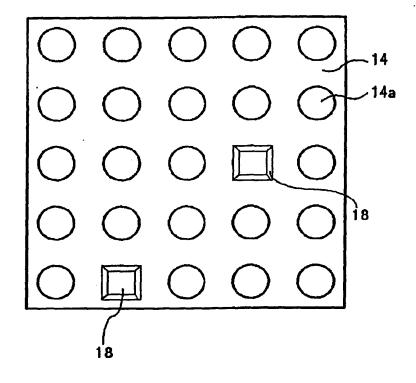


FIG. 14b



18: DIRECTION ALIGNING ELECTRODE

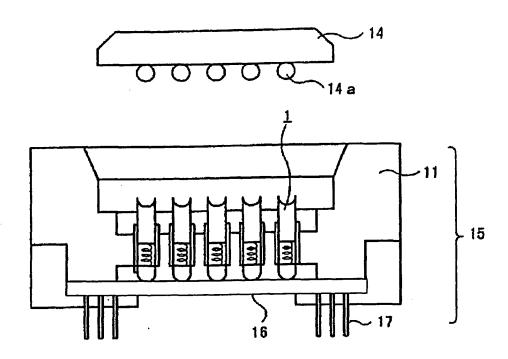
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INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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F I G. 15



16: CIRCUIT BOARD

17: CONNECTING PIN

TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

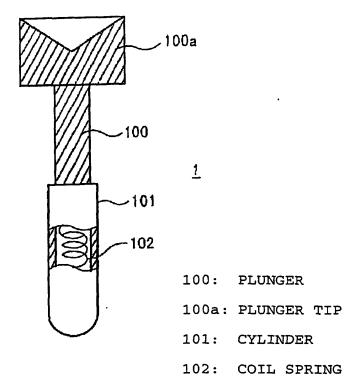
AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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FIG. 16

2 -551



3

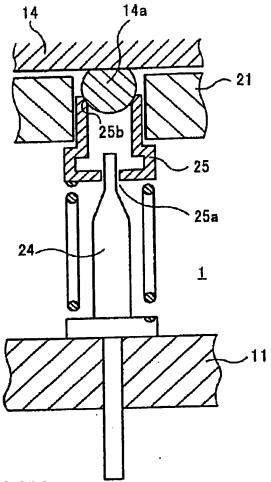
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

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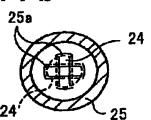
INVENTOR(S): SHIGEKI MAEKAWA ET AL.

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FIG. 17a



F I G. 17b



21: FLOATING PLATE

24: TWISTED LEAD PLATE

25: CONTACTING PART

25a: RECTANGULAR LEAD HOLE

25b: CONTACTING PART HAVING

TAPER-LIKE INNER PERIPHERY

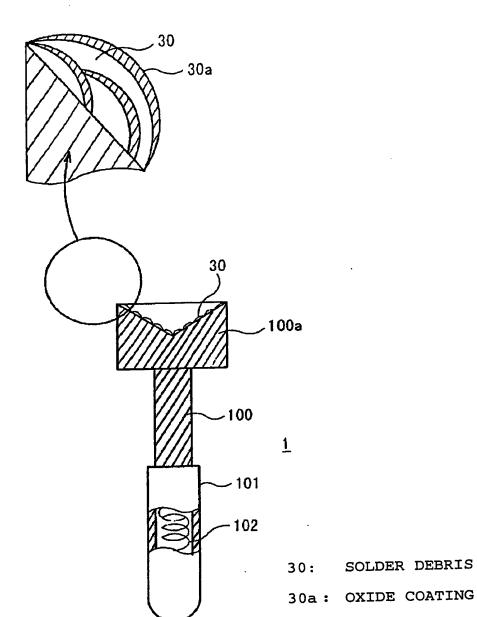
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F I G. 18

3.364



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